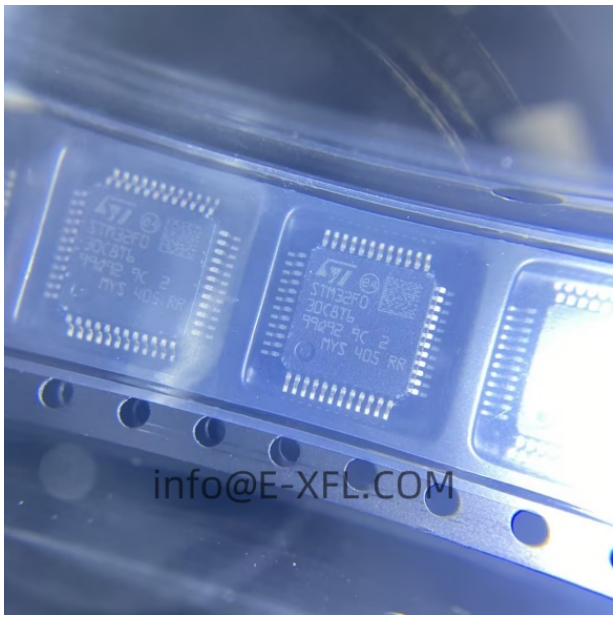

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	I²C, SPI, UART/USART
Peripherals	DMA, POR, PWM, WDT
Number of I/O	39
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	2.4V ~ 3.6V
Data Converters	A/D 12x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f030c8t6tr

Contents

List of tables

3.4 Cyclic redundancy check calculation unit (CRC)

The CRC (cyclic redundancy check) calculation unit is used to get a CRC code using a configurable generator polynomial value and size.

Among other applications, CRC-based techniques are used to verify data transmission or storage integrity. In the scope of the EN/IEC 60335-1 standard, they offer a means of verifying the Flash memory integrity. The CRC calculation unit helps compute a signature of the software during runtime, to be compared with a reference signature generated at link-time and stored at a given memory location.

3.5 Power management

3.5.1 Power supply schemes

- V_{DD} = 2.4 to 3.6 V: external power supply for I/Os and the internal regulator. Provided externally through VDD pins.
- V_{DDA} = from V_{DD} to 3.6 V: external analog power supply for ADC, Reset blocks, RCs and PLL. The V_{DDA} voltage level must be always greater or equal to the V_{DD} voltage level and must be provided first.

For more details on how to connect power pins, refer to *Figure 12: Power supply scheme*.

3.5.2 Power supply supervisors

The device has integrated power-on reset (POR) and power-down reset (PDR) circuits. They are always active, and ensure proper operation above a threshold of 2 V. The device remains in reset mode when the monitored supply voltage is below a specified threshold, $V_{POR/PDR}$, without the need for an external reset circuit.

- The POR monitors only the V_{DD} supply voltage. During the startup phase it is required that V_{DDA} should arrive first and be greater than or equal to V_{DD}.
- The PDR monitors both the V_{DD} and V_{DDA} supply voltages, however the V_{DDA} power supply supervisor can be disabled (by programming a dedicated Option bit) to reduce the power consumption if the application design ensures that V_{DDA} is higher than or equal to V_{DD}.

3.5.3 Voltage regulator

The regulator has two operating modes and it is always enabled after reset.

- Main (MR) is used in normal operating mode (Run).
- Low power (LPR) can be used in Stop mode where the power demand is reduced.

In Standby mode, it is put in power down mode. In this mode, the regulator output is in high impedance and the kernel circuitry is powered down, inducing zero consumption (but the contents of the registers and SRAM are lost).

3.10 Analog to digital converter (ADC)

The 12-bit analog to digital converter has up to 16 external and two internal (temperature sensor, voltage reference measurement) channels and performs conversions in single-shot or scan modes. In scan mode, automatic conversion is performed on a selected group of analog inputs.

The ADC can be served by the DMA controller.

An analog watchdog feature allows very precise monitoring of the converted voltage of one, some or all selected channels. An interrupt is generated when the converted voltage is outside the programmed thresholds.

3.10.1 Temperature sensor

The temperature sensor (TS) generates a voltage V_{SENSE} that varies linearly with temperature.

The temperature sensor is internally connected to the ADC_IN16 input channel which is used to convert the sensor output voltage into a digital value.

The sensor provides good linearity but it has to be calibrated to obtain good overall accuracy of the temperature measurement. As the offset of the temperature sensor varies from chip to chip due to process variation, the uncalibrated internal temperature sensor is suitable for applications that detect temperature changes only.

To improve the accuracy of the temperature sensor measurement, each device is individually factory-calibrated by ST. The temperature sensor factory calibration data are stored by ST in the system memory area, accessible in read-only mode.

Table 3. Temperature sensor calibration values

Calibration value name	Description	Memory address
TS_CAL1	TS ADC raw data acquired at a temperature of 30 °C (±5 °C), V_{DDA}= 3.3 V (±10 mV)	0x1FFF F7B8 - 0x1FFF F7B9

3.10.2 Internal voltage reference (V_{REFINT})

The internal voltage reference (V_{REFINT}) provides a stable (bandgap) voltage output for the ADC. V_{REFINT} is internally connected to the ADC_IN17 input channel. The precise voltage of V_{REFINT} is individually measured for each part by ST during production test and stored in the system memory area. It is accessible in read-only mode.

Table 4. Internal voltage reference calibration values

Calibration value name	Description	Memory address
VREFINT_CAL	Raw data acquired at a temperature of 30 °C (±5 °C), V_{DDA}= 3.3 V (±10 mV)	0x1FFF F7BA - 0x1FFF F7BB

Table 8 gives an overview of features as implemented on the available USART interfaces. All USART interfaces can be served by the DMA controller.

Table 8. STM32F0x0 USART implementation(1)

USART modes/ features	STM32F030x4 STM32F030x6	STM32F030x8		STM32F030xC			
	USART1	USART1	USART2	USART1 USART2 USART3	USART4	USART5	USART6
Hardware flow control for modem	X	X	X	X	X	-	-
Continuous communication using DMA	X	X	X	X	X	X	X
Multiprocessor communication	X	X	X	X	X	X	X
Synchronous mode	X	X	X	X	X	X	-
Smartcard mode	-	-	-	-	-	-	-
Single-wire Half-duplex communication	X	X	X	X	X	X	X
IrDA SIR ENDEC block	-	-	-	-	-	-	-
LIN mode	-	-	-	-	-	-	-
Dual clock domain and wakeup from Stop mode	-	-	-	-	-	-	-
Receiver timeout interrupt	X	X	-	X	-	-	-
Modbus communication	-	-	-	-	-	-	-
Auto baud rate detection (supported modes)	2	2	-	4	-	-	-
Driver Enable	X	X	X	X	X	X	X
USART data length	8 and 9 bits			7, 8 and 9 bits			

1. **X = supported.**

3.15 Serial peripheral interface (SPI)

Up to two SPIs are able to communicate up to 18 Mbit/s in slave and master modes in full-duplex and half-duplex communication modes. The 3-bit prescaler gives 8 master mode frequencies and the frame size is configurable from 4 bits to 16 bits.

SPI1 and SPI2 are identical and implement the set of features shown in the following table.

4 Pinouts and pin descriptions

Figure 3. LQFP64 64-pin package pinout (top view), for STM32F030x4/6/8 devices

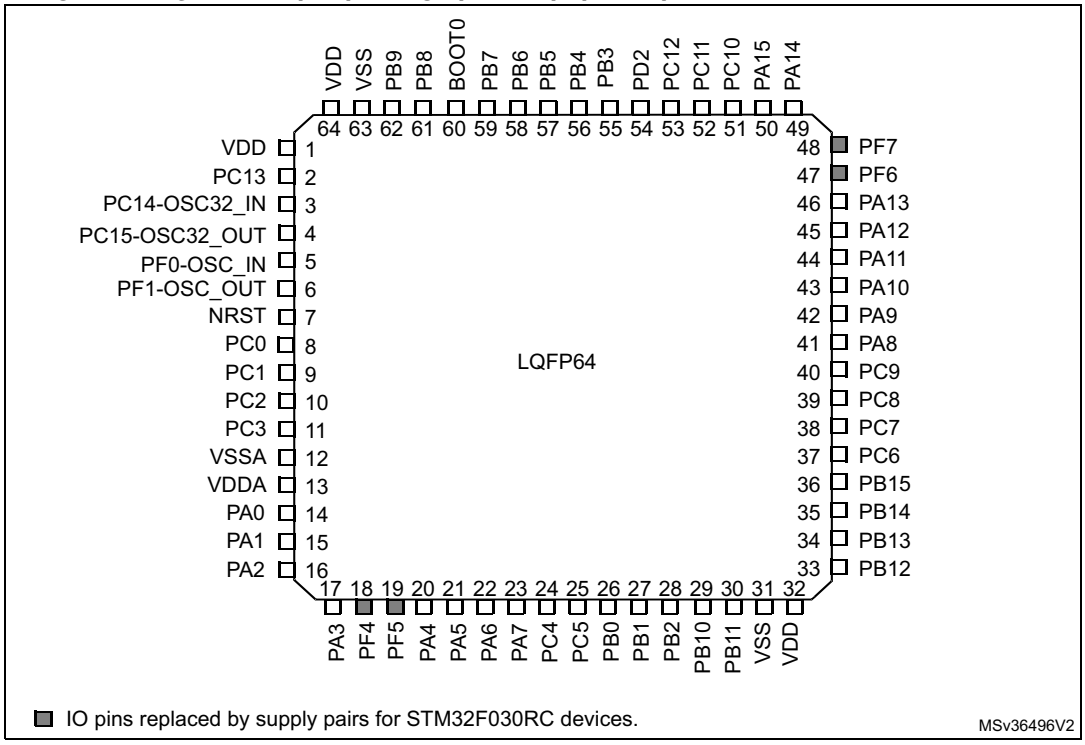


Figure 4. LQFP64 64-pin package pinout (top view), for STM32F030RC devices

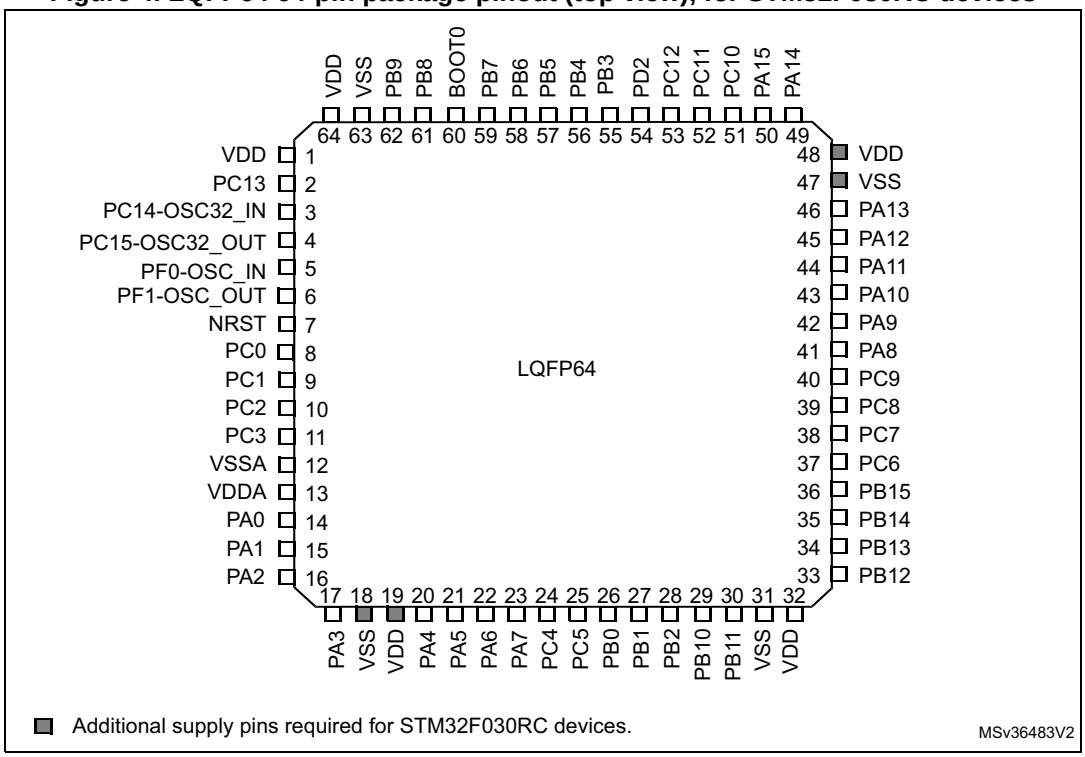


Figure 5. LQFP48 48-pin package pinout (top view), for STM32F030x4/6/8 devices

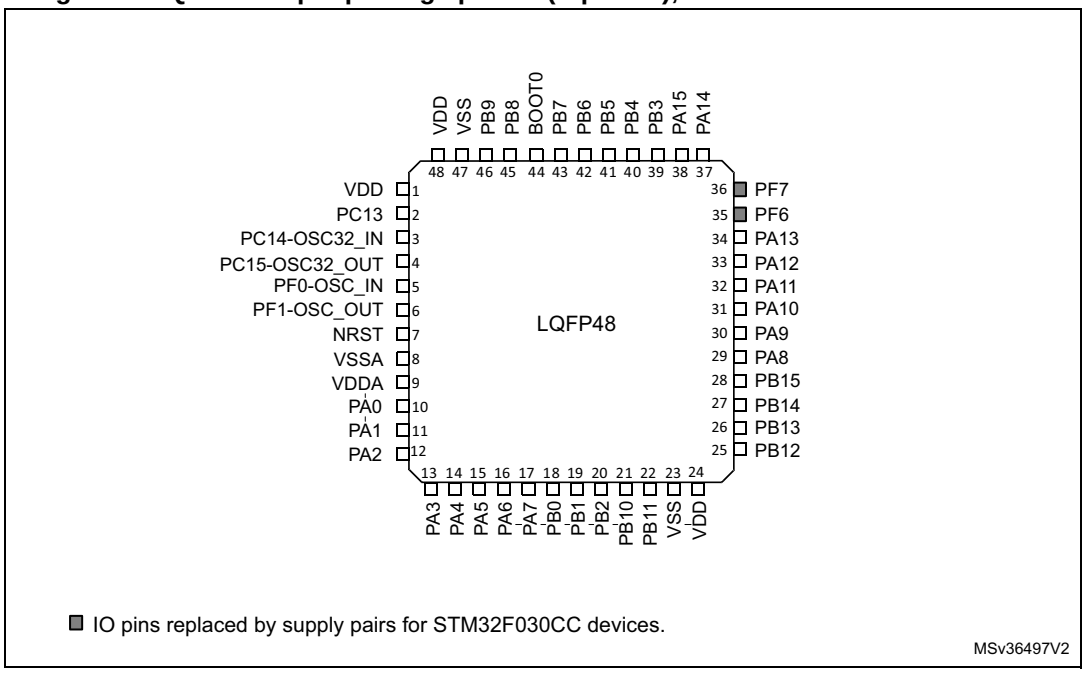


Figure 6. LQFP48 48-pin package pinout (top view), for STM32F030CC devices

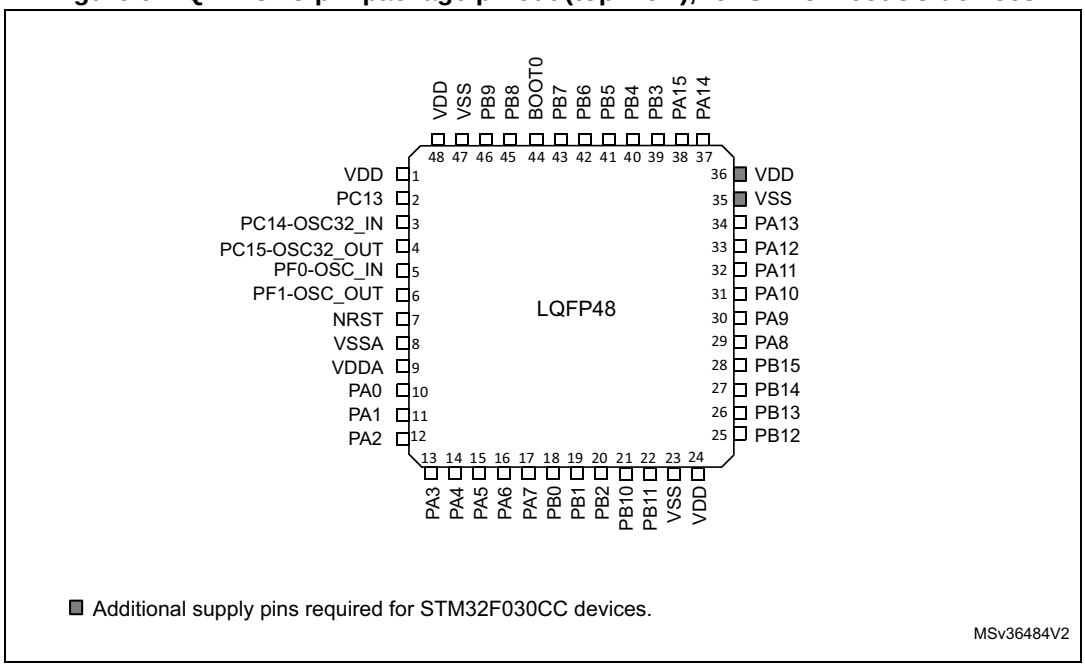


Table 11. STM32F030x4/6/8/C pin definitions (continued)

Pin number				Pin name (function after reset)	Pin type	I/O structure	Notes	Pin functions	
LQFP64	LQFP48	LQFP32	TSSOP20					Alternate functions	Additional functions
34	26	-	-	PB13	I/O	FT	-	SPI1_SCK(2), SPI2_SCK(3)(5), I2C2_SCL(5), TIM1_CH1N, USART3_CTS(5)	-
35	27	-	-	PB14	I/O	FT	-	SPI1_MISO(2), SPI2_MISO(3)(5), I2C2_SDA(5), TIM1_CH2N, TIM15_CH1(3)(5), USART3_RTS(5)	-
36	28	-	-	PB15	I/O	FT	-	SPI1_MOSI(2), SPI2_MOSI(3)(5), TIM1_CH3N, TIM15_CH1N(3)(5), TIM15_CH2(3)(5)	RTC_REFIN, WKPU7(5)
37	-	-	-	PC6	I/O	FT	-	TIM3_CH1	-
38	-	-	-	PC7	I/O	FT	-	TIM3_CH2	-
39	-	-	-	PC8	I/O	FT	-	TIM3_CH3	-
40	-	-	-	PC9	I/O	FT	-	TIM3_CH4	-
41	29	18	-	PA8	I/O	FT	-	USART1_CK, TIM1_CH1, EVENTOUT, MCO	-
42	30	19	17	PA9	I/O	FT	-	USART1_TX, TIM1_CH2, TIM15_BKIN(3)(5) I2C1_SCL(2)(5)	-
43	31	20	18	PA10	I/O	FT	-	USART1_RX, TIM1_CH3, TIM17_BKIN I2C1_SDA(2)(5)	-
44	32	21	-	PA11	I/O	FT	-	USART1_CTS, TIM1_CH4, EVENTOUT, I2C2_SCL(5)	-
45	33	22	-	PA12	I/O	FT	-	USART1_RTS, TIM1_ETR, EVENTOUT, I2C2_SDA(5)	-

Table 12. Alternate functions selected through GPIOA_AFR registers for port A

Pin name	AF0	AF1	AF2	AF3	AF4	AF5	AF6
PA0	-	USART1_CTS(2)	-	-	USART4_TX(1)	-	-
		USART2_CTS(1)(3)					
PA1	EVENTOUT	USART1_RTS(2)	-	-	USART4_RX(1)	TIM15_CH1N(1)	-
		USART2_RTS(1)(3)					
PA2	TIM15_CH1(1)(3)	USART1_TX(2)	-	-	-	-	-
		USART2_TX(1)(3)					
PA3	TIM15_CH2(1)(3)	USART1_RX(2)	-	-	-	-	-
		USART2_RX(1)(3)					
PA4	SPI1_NSS	USART1_CK(2)	-	-	TIM14_CH1	USART6_TX(1)	-
		USART2_CK(1)(3)					
PA5	SPI1_SCK	-	-	-	-	USART6_RX(1)	-
PA6	SPI1_MISO	TIM3_CH1	TIM1_BKIN	-	USART3_CTS(1)	TIM16_CH1	EVENTOUT
PA7	SPI1_MOSI	TIM3_CH2	TIM1_CH1N	-	TIM14_CH1	TIM17_CH1	EVENTOUT
PA8	MCO	USART1_CK	TIM1_CH1	EVENTOUT	-	-	-
PA9	TIM15_BKIN(1)(3)	USART1_TX	TIM1_CH2	-	I2C1_SCL(1)(2)	MCO(1)	-
PA10	TIM17_BKIN	USART1_RX	TIM1_CH3	-	I2C1_SDA(1)(2)	-	-
PA11	EVENTOUT	USART1_CTS	TIM1_CH4	-	-	SCL	-

6.2 Absolute maximum ratings

Stresses above the absolute maximum ratings listed in *Table 18: Voltage characteristics*, *Table 19: Current characteristics* and *Table 20: Thermal characteristics* may cause permanent damage to the device. These are stress *ratings* only and functional operation of the device at these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 18. Voltage characteristics(1)

Symbol	Ratings	Min	Max	Unit
V_{DD}–V_{SS}	External main supply voltage	-0.3	4.0	V
V_{DDA}–V_{SS}	External analog supply voltage	-0.3	4.0	V
V_{DD}–V_{DDA}	Allowed voltage difference for $V_{DD} > V_{DDA}$	-	0.4	V
V_{IN}(2)	Input voltage on FT and FTf pins	V_{SS} –0.3	V_{DDIOx} + 4.0 (3)	V
	Input voltage on TTa pins	V_{SS} –0.3	4.0	V
	BOOT0	0	V_{DDIOx} + 4.0 (3)	V
	Input voltage on any other pin	V_{SS} –0.3	4.0	V
$\lvert\Delta V_{DDx}\rvert$	Variations between different V_{DD} power pins	-	50	mV
$\lvert V_{SSx} - V_{SS}\rvert$	Variations between all the different ground pins	-	50	mV
$V_{ESD(HBM)}$	Electrostatic discharge voltage (human body model)	see *Section 6.3.12: Electrical sensitivity characteristics*		-

1. All main power (V_{DD}, V_{DDA}) and ground (V_{SS}, V_{SSA}) pins must always be connected to the external power supply, in the permitted range.
2. V_{IN} maximum must always be respected. Refer to *Table 19: Current characteristics* for the maximum allowed injected current values.
3. V_{DDIOx} is internally connected with VDD pin.

Table 23. Embedded reset and power control block characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{PDRhyst}$	PDR hysteresis	-	-	40	-	mV
$t_{RSTTEMPO}$ (4)	Reset temporization	-	1.50	2.50	4.50	ms

1. The PDR detector monitors V_{DD} and also V_{DDA} (if kept enabled in the option bytes). The POR detector monitors only V_{DD}.
2. The product behavior is guaranteed by design down to the minimum $V_{POR/PDR}$ value.
3. Data based on characterization results, not tested in production.
4. Guaranteed by design, not tested in production.

6.3.4 Embedded reference voltage

The parameters given in *Table 24* are derived from tests performed under the ambient temperature and supply voltage conditions summarized in *Table 21: General operating conditions*.

Table 24. Embedded internal reference voltage

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{REFINT}	Internal reference voltage	-40°C < T_A < +85°C	1.2	1.23	1.25	V
t_{START}	ADC_IN17 buffer startup time	-	-	-	10(1)	µs
$t_{S\_vrefint}$	ADC sampling time when reading the internal reference voltage	-	4 (1)	-	-	µs
ΔV_{REFINT}	Internal reference voltage spread over the temperature range	V_{DDA} = 3 V	-	-	10(1)	mV
T_{Coeff}	Temperature coefficient	-	-100(1)	-	100(1)	ppm/°C

1. Guaranteed by design, not tested in production.

6.3.5 Supply current characteristics

The current consumption is a function of several parameters and factors such as the operating voltage, ambient temperature, I/O pin loading, device software configuration, operating frequencies, I/O pin switching rate, program location in memory and executed binary code.

The current consumption is measured as described in *Figure 13: Current consumption measurement scheme*.

All Run-mode current consumption measurements given in this section are performed with a reduced code that gives a consumption equivalent to CoreMark code.

Low-speed external user clock generated from an external source

In bypass mode the LSE oscillator is switched off and the input pin is a standard GPIO.

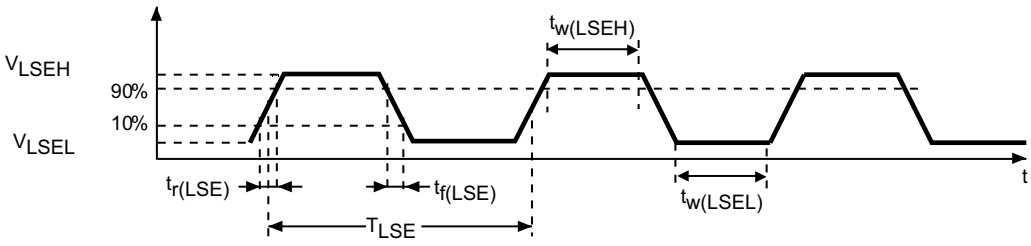
The external clock signal has to respect the I/O characteristics in *Section 6.3.14*. However, the recommended clock input waveform is shown in *Figure 15*.

Table 32. Low-speed external user clock characteristics

Symbol	Parameter(1)	Min	Typ	Max	Unit
f_{LSE_ext}	User external clock source frequency	-	32.768	1000	kHz
V_{LSEH}	OSC32_IN input pin high level voltage	0.7 V_{DDIOx}	-	V_{DDIOx}	V
V_{LSEL}	OSC32_IN input pin low level voltage	V_{SS}	-	0.3 V_{DDIOx}	
$t_{w(LSEH)}$ $t_{w(LSEL)}$	OSC32_IN high or low time	450	-	-	ns
$t_{r(LSE)}$ $t_{f(LSE)}$	OSC32_IN rise or fall time	-	-	50	

1. Guaranteed by design, not tested in production.

Figure 15. Low-speed external clock source AC timing diagram



High-speed external clock generated from a crystal/ceramic resonator

The high-speed external (HSE) clock can be supplied with a 4 to 32 MHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on design simulation results obtained with typical external components specified in *Table 33*. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

Table 33. HSE oscillator characteristics

Symbol	Parameter	Conditions(1)	Min(2)	Typ	Max(2)	Unit
f_{OSC_IN}	Oscillator frequency	-	4	8	32	MHz
R_F	Feedback resistor	-	-	200	-	kΩ

Table 45. I/O current injection susceptibility

Symbol	Description	Functional susceptibility		Unit
		Negative injection	Positive injection	
I_{INJ}	Injected current on BOOT0 and PF1 pins	-0	NA	mA
	Injected current on PA9, PB3, PB13, PF11 pins with induced leakage current on adjacent pins less than 50 µA	-5	NA	
	Injected current on PA11 and PA12 pins with induced leakage current on adjacent pins less than -1 mA	-5	NA	
	Injected current on all other FT and FTf pins	-5	NA	
	Injected current on PB0 and PB1 pins	-5	NA	
	Injected current on PC0 pin	-0	+5	
	Injected current on all other TTa, TC and RST pins	-5	+5	

6.3.14 I/O port characteristics

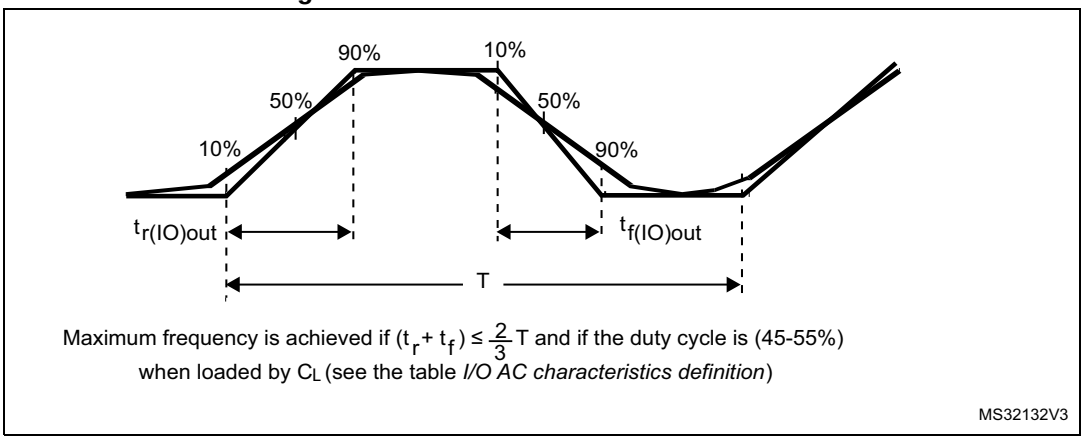
General input/output characteristics

Unless otherwise specified, the parameters given in *Table 46* are derived from tests performed under the conditions summarized in *Table 21: General operating conditions*. All I/Os are designed as CMOS- and TTL-compliant (except BOOT0).

Table 46. I/O static characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{IL}	Low level input voltage	TC and TTa I/O	-	-	$0.3\ V_{DDIOx}+0.07$(1)	V
		FT and FTf I/O	-	-	$0.475\ V_{DDIOx}-0.2$(1)	
		BOOT0	-	-	$0.3\ V_{DDIOx}-0.3$(1)	
		All I/Os except BOOT0 pin	-	-	$0.3\ V_{DDIOx}$	
V_{IH}	High level input voltage	TC and TTa I/O	$0.445\ V_{DDIOx}+0.398$(1)	-	-	V
		FT and FTf I/O	$0.5\ V_{DDIOx}+0.2$(1)	-	-	
		BOOT0	$0.2\ V_{DDIOx}+0.95$(1)	-	-	
		All I/Os except BOOT0 pin	$0.7\ V_{DDIOx}$	-	-	
V_{hys}	Schmitt trigger hysteresis	TC and TTa I/O	-	200(1)	-	mV
		FT and FTf I/O	-	100(1)	-	
		BOOT0	-	300(1)	-	

Figure 20. I/O AC characteristics definition



6.3.15 NRST pin characteristics

The NRST pin input driver uses the CMOS technology. It is connected to a permanent pull-up resistor, R_{PU}.

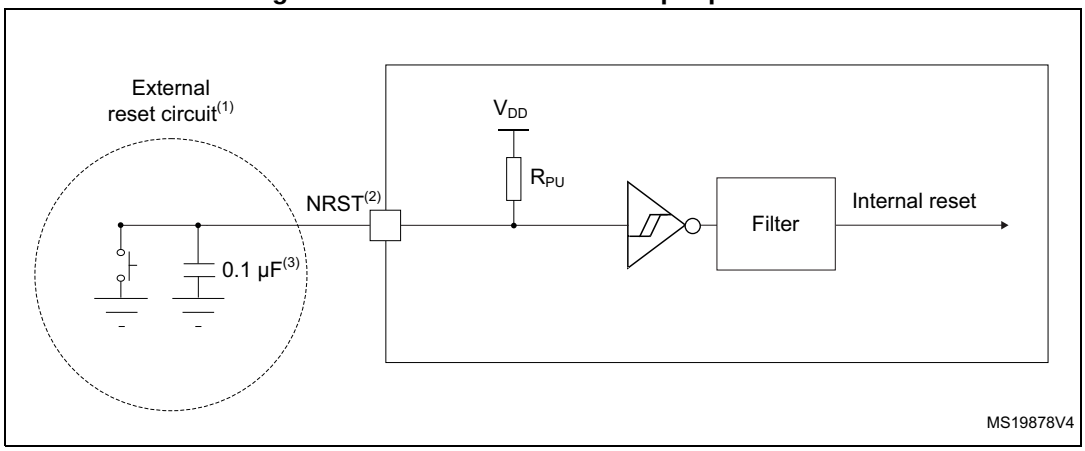
Unless otherwise specified, the parameters given in the table below are derived from tests performed under the ambient temperature and supply voltage conditions summarized in *Table 21: General operating conditions*.

Table 49. NRST pin characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IL(NRST)}$	NRST input low level voltage	-	-	-	$0.3\ V_{DD}+0.07^{(1)}$	V
$V_{IH(NRST)}$	NRST input high level voltage	-	$0.445\ V_{DD}+0.398^{(1)}$	-	-	
$V_{hys(NRST)}$	NRST Schmitt trigger voltage hysteresis	-	-	200	-	mV
R_{PU}	Weak pull-up equivalent resistor(2)	$V_{IN} = V_{SS}$	25	40	55	kΩ
$V_{F(NRST)}$	NRST input filtered pulse	-	-	-	$100^{(1)}$	ns
$V_{NF(NRST)}$	NRST input not filtered pulse	$2.7 < V_{DD} < 3.6$	$300^{(3)}$	-	-	ns
		$2.4 < V_{DD} < 3.6$	$500^{(3)}$	-	-	

1. Data based on design simulation only. Not tested in production.
2. The pull-up is designed with a true resistance in series with a switchable PMOS. This PMOS contribution to the series resistance is minimal (~10% order).
3. Data based on design simulation only. Not tested in production.

Figure 21. Recommended NRST pin protection



1. The external capacitor protects the device against parasitic resets.
2. The user must ensure that the level on the NRST pin can go below the $V_{IL(NRST)}$ max level specified in *Table 49: NRST pin characteristics*. Otherwise the reset will not be taken into account by the device.

6.3.16 12-bit ADC characteristics

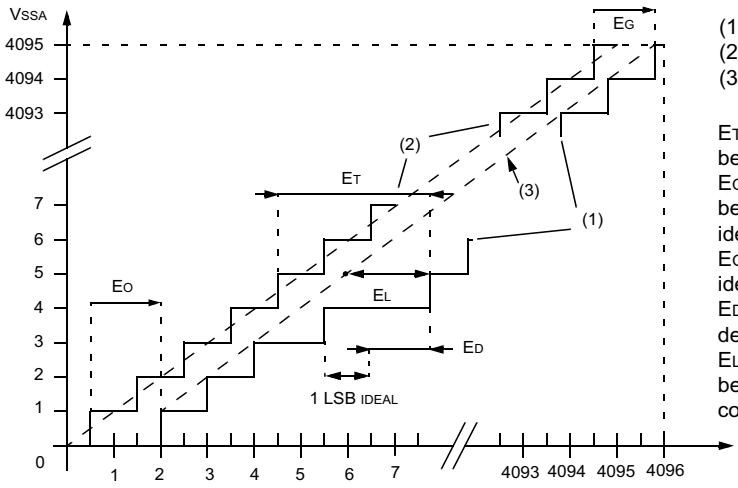
Unless otherwise specified, the parameters given in *Table 50* are preliminary values derived from tests performed under ambient temperature, f_{PCLK} frequency and V_{DDA} supply voltage conditions summarized in *Table 21: General operating conditions*.

Note: It is recommended to perform a calibration after each power-up.

Table 50. ADC characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DDA}	Analog supply voltage for ADC ON	-	2.4	-	3.6	V
$I_{DDA\ (ADC)}$	Current consumption of the ADC(1)	$V_{DD} = V_{DDA} = 3.3$ V	-	0.9	-	mA
f_{ADC}	ADC clock frequency	-	0.6	-	14	MHz
f_S(2)	Sampling rate	-	0.05	-	1	MHz
f_{TRIG}(2)	External trigger frequency	f_{ADC} = 14 MHz	-	-	823	kHz
		-	-	-	17	$1/f_{ADC}$
V_{AIN}	Conversion voltage range	-	0	-	V_{DDA}	V
R_{AIN}(2)	External input impedance	See *Equation 1* and *Table 51* for details	-	-	50	kΩ
R_{ADC}(2)	Sampling switch resistance	-	-	-	1	kΩ
C_{ADC}(2)	Internal sample and hold capacitor	-	-	-	8	pF

Figure 22. ADC accuracy characteristics

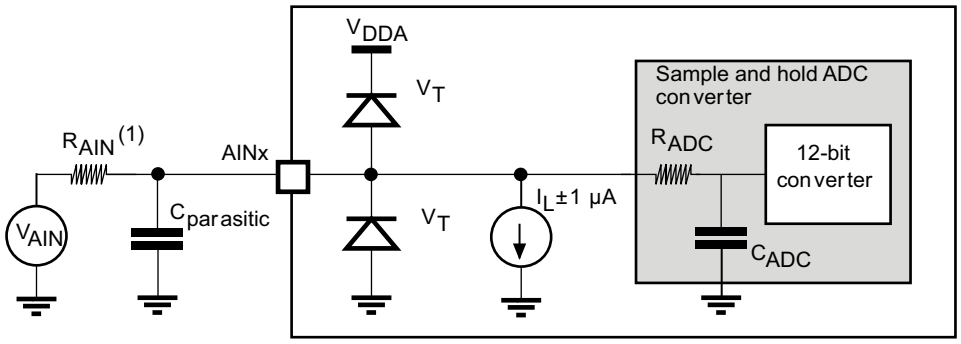


(1) Example of an actual transfer curve
(2) The ideal transfer curve
(3) End point correlation line

E_T = Total Unajusted Error: maximum deviation between the actual and ideal transfer curves.
E_O = Offset Error: maximum deviation between the first actual transition and the first ideal one.
E_G = Gain Error: deviation between the last ideal transition and the last actual one.
E_D = Differential Linearity Error: maximum deviation between actual steps and the ideal ones.
E_L = Integral Linearity Error: maximum deviation between any actual transition and the end point correlation line.

MS19880V2

Figure 23. Typical connection diagram using the ADC



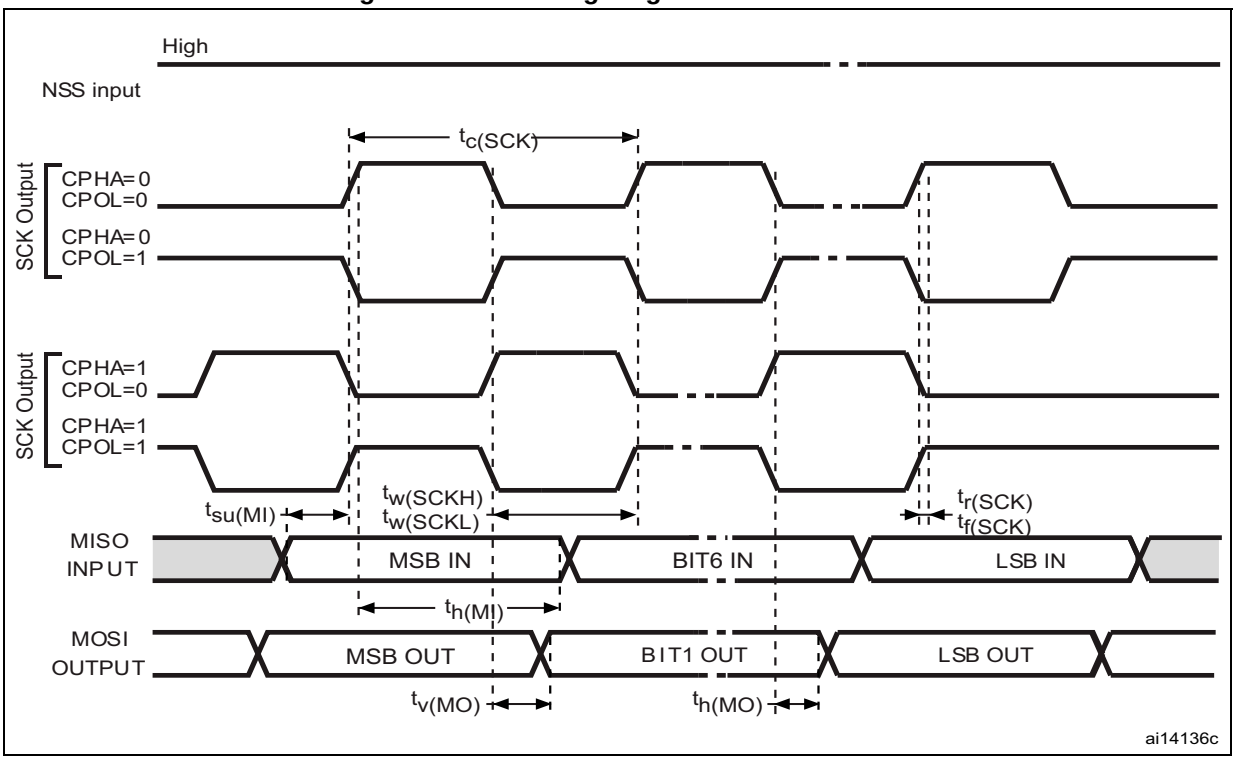
MS33900V1

1. Refer to *Table 50: ADC characteristics* for the values of R_{AIN}, R_{ADC} and C_{ADC}.
2. $C_{parasitic}$ represents the capacitance of the PCB (dependent on soldering and PCB layout quality) plus the pad capacitance (roughly 7 pF). A high $C_{parasitic}$ value will downgrade conversion accuracy. To remedy this, f_{ADC} should be reduced.

General PCB design guidelines

Power supply decoupling should be performed as shown in *Figure 12: Power supply scheme*. The 10 nF capacitor should be ceramic (good quality) and it should be placed as close as possible to the chip.

Figure 26. SPI timing diagram - master mode



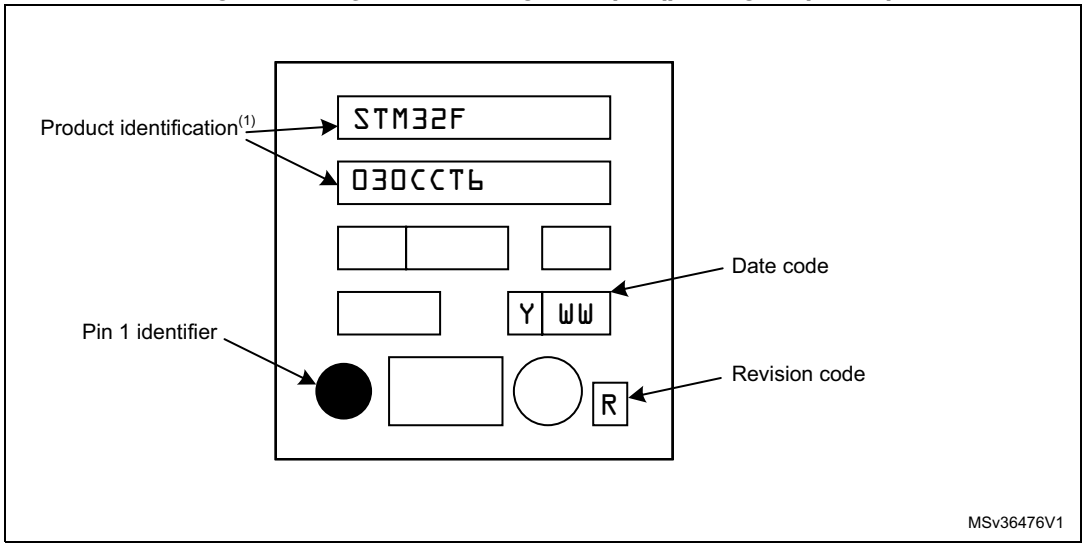
1. Measurement points are done at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD}.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 32. LQFP48 marking example (package top view)

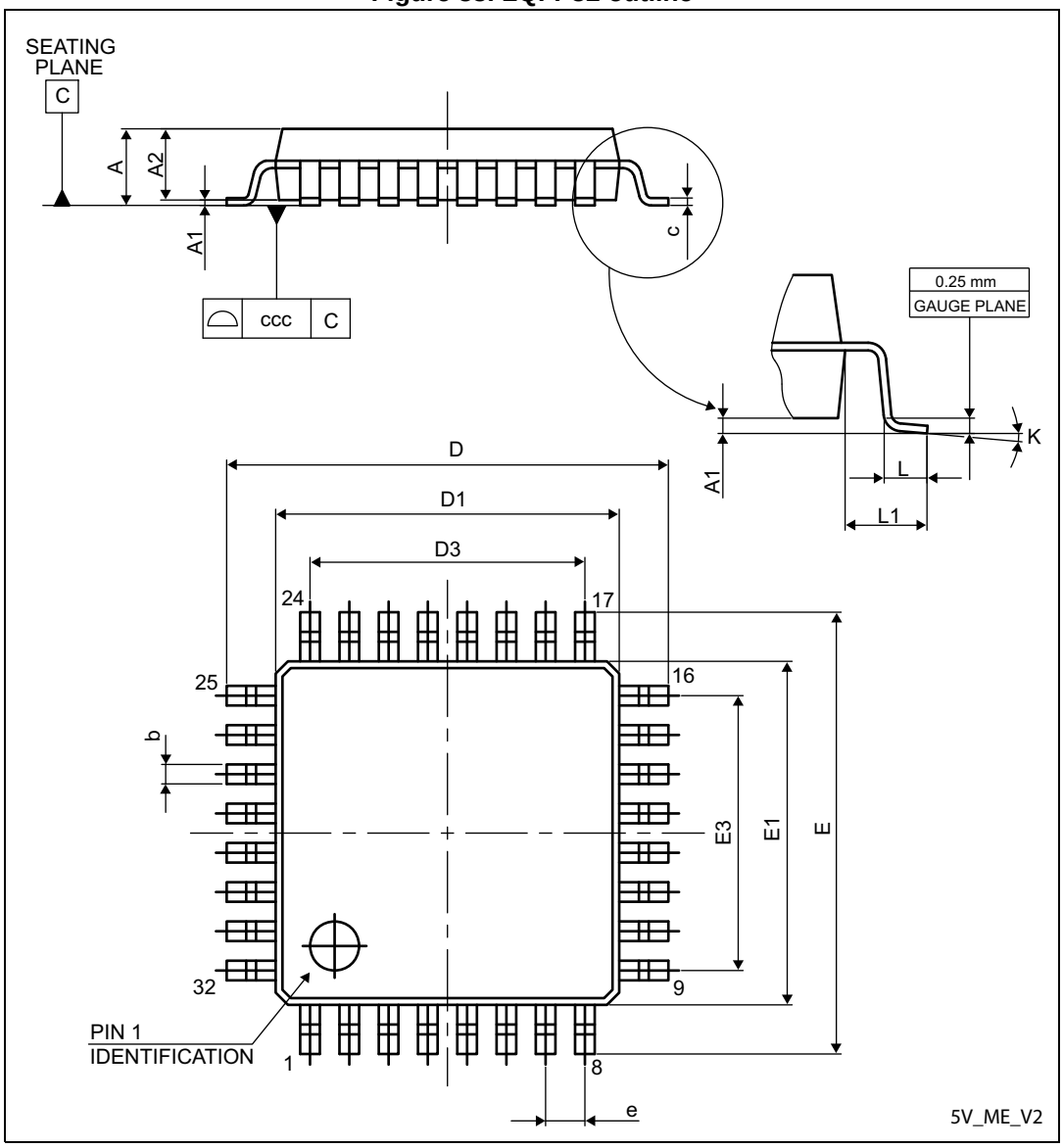


1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

7.3 LQFP32 package information

LQFP32 is a 32-pin, 7 x 7 mm low-profile quad flat package

Figure 33. LQFP32 outline



1. Drawing is not to scale.

Table 61. LQFP32 mechanical data

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571